



**ALPHA & OMEGA**  
SEMICONDUCTOR

**AON2810**

**30V Dual N-Channel AlphaMOS**

### General Description

- Latest Trench Power AlphaMOS (αMOS LV) technology
- Very Low  $R_{DS(ON)}$  at 2.5V  $V_{GS}$
- Low Gate Charge
- ESD protection
- RoHS and Halogen-Free Compliant

### Application

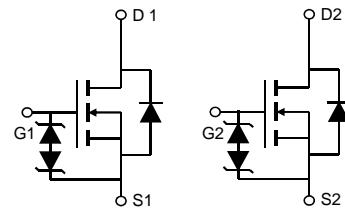
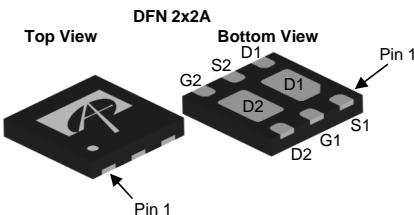
- DC/DC Converters

### Product Summary

$V_{DS}$	30V
$I_D$ (at $V_{GS}=10V$ )	2A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 44 mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$ )	< 52 mΩ
$R_{DS(ON)}$ (at $V_{GS}=2.5V$ )	< 74 mΩ

### Typical ESD protection

HBM Class 3A



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current <sup>G</sup>	$I_D$	2	A
$T_A=70^\circ\text{C}$		1.6	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	8	
$V_{DS}$ Spike	$V_{SPIKE}$	36	V
$T_A=25^\circ\text{C}$		2.5	W
$T_A=70^\circ\text{C}$		1.6	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \leq 10\text{s}$	$R_{\theta JA}$	40	50	°C/W
Maximum Junction-to-Ambient <sup>A D</sup> Steady-State		65	80	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 10\text{V}$			$\pm 10$	$\mu\text{A}$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.6	1	1.4	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=2\text{A}$ $T_J=125^\circ\text{C}$	36	44		$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=1\text{A}$	50	61		
		$V_{GS}=2.5\text{V}, I_D=1\text{A}$	41	52		
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=2\text{A}$		9.5		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.75	1	V
$I_S$	Maximum Body-Diode Continuous Current <sup>G</sup>				2	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		235		pF
$C_{\text{oss}}$	Output Capacitance			75		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			15		pF
$R_g$	Gate resistance	$f=1\text{MHz}$	4	8	12	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=2\text{A}$		4.5	10	nC
$Q_g(4.5\text{V})$	Total Gate Charge			2.2	6	nC
$Q_{\text{gs}}$	Gate Source Charge			0.3		nC
$Q_{\text{gd}}$	Gate Drain Charge			0.7		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=7.5\Omega, R_{\text{GEN}}=3\Omega$		3		ns
$t_r$	Turn-On Rise Time			3		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			24		ns
$t_f$	Turn-Off Fall Time			6		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=2\text{A}, dI/dt=100\text{A}/\mu\text{s}$		7.2		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=2\text{A}, dI/dt=100\text{A}/\mu\text{s}$		1.3		nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

B. The Power dissipation  $P_D$  is based on  $R_{\theta JA}$   $t \leq 10\text{s}$  value and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

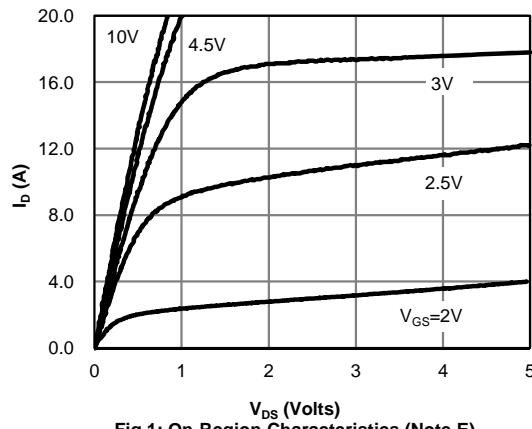
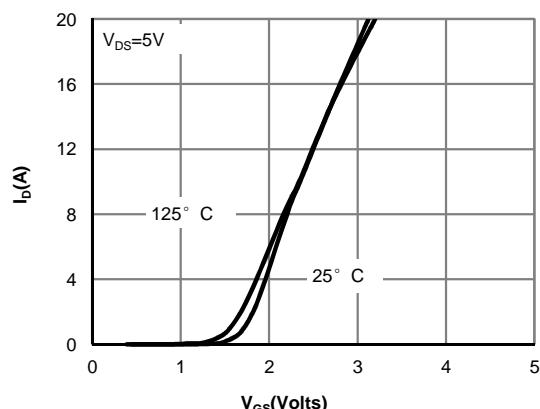
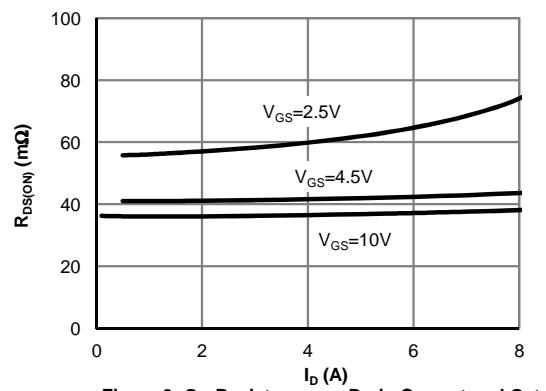
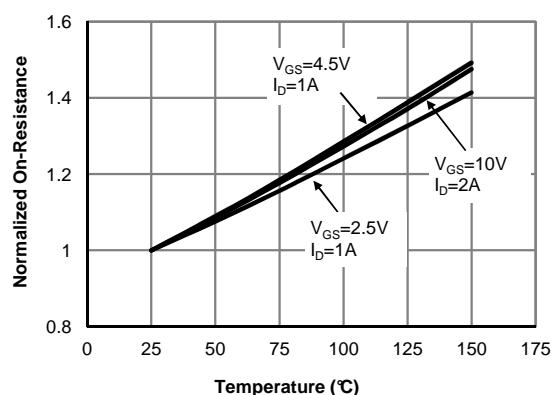
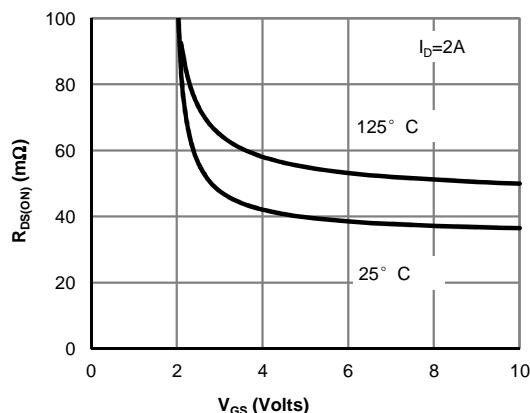
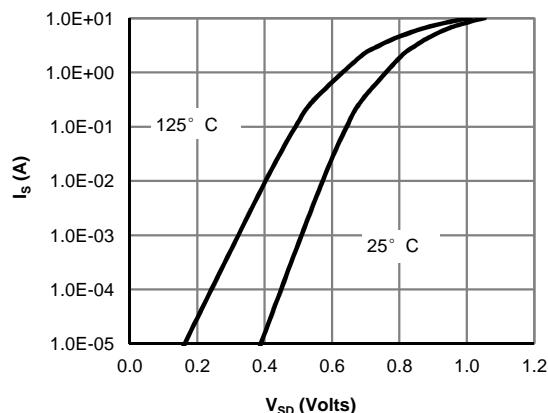
E. The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.

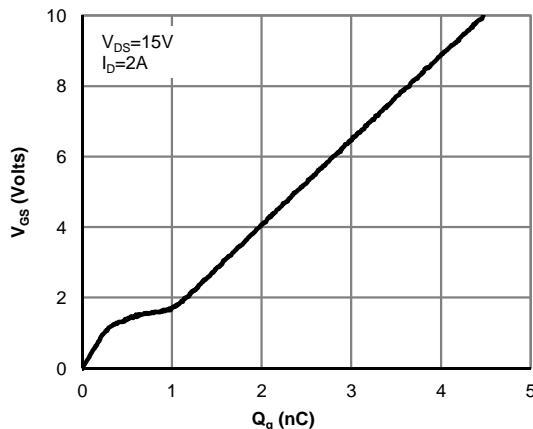
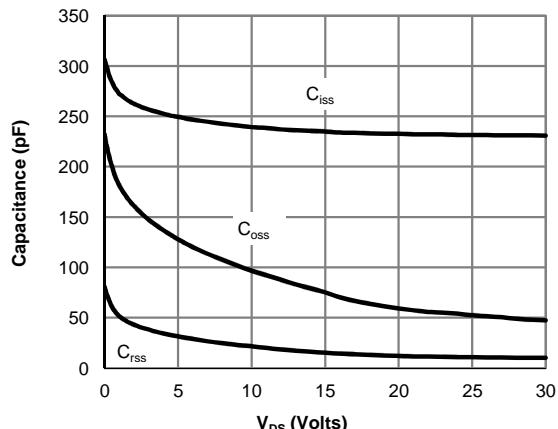
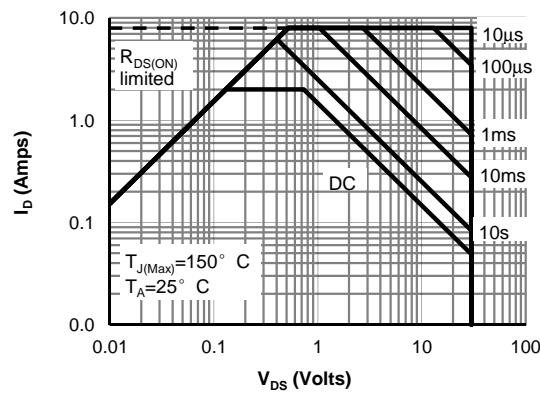
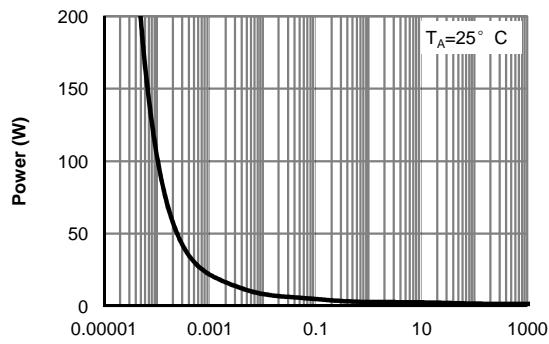
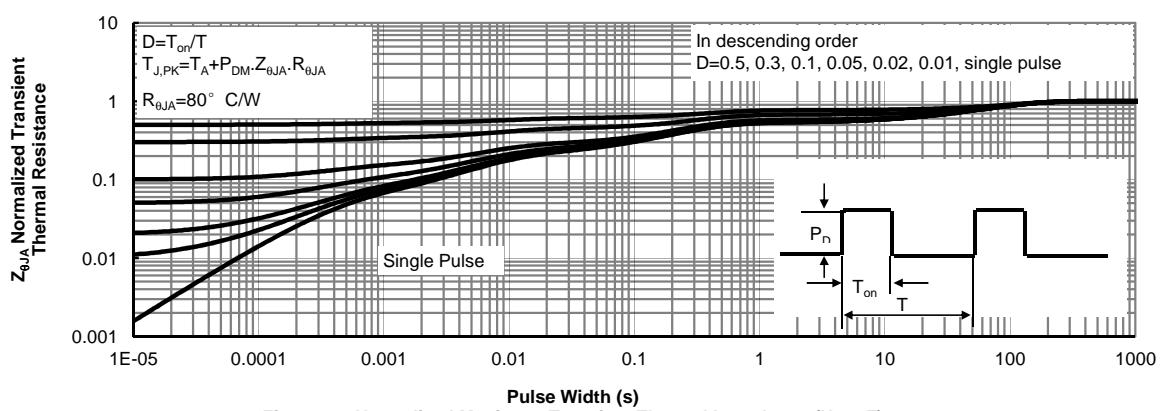
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.

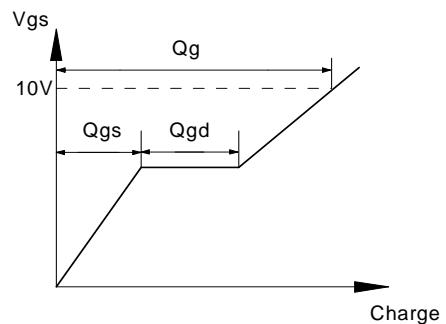
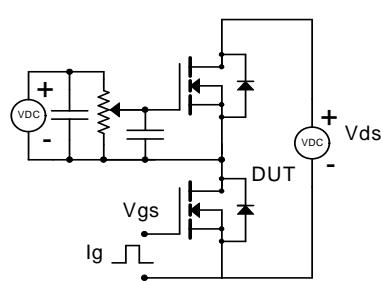
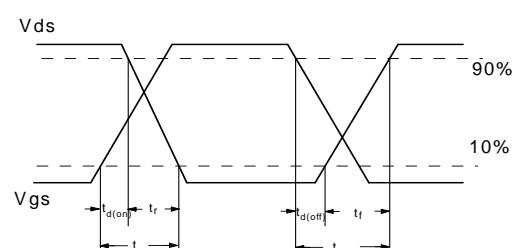
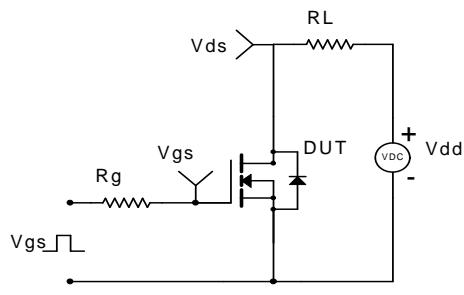
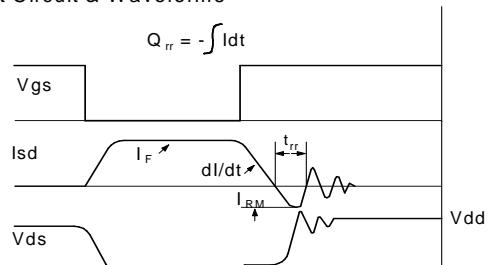
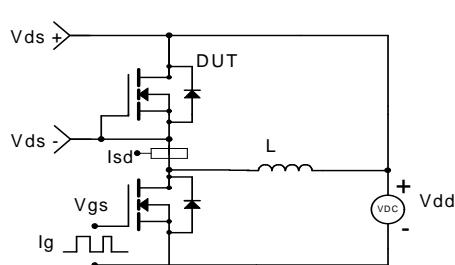
G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Fig 1: On-Region Characteristics (Note E)**

**Figure 2: Transfer Characteristics (Note E)**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)**

**Figure 4: On-Resistance vs. Junction Temperature (Note E)**

**Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)**

**Figure 6: Body-Diode Characteristics (Note E)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area (Note F)**

**Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)**

**Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)**

**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

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